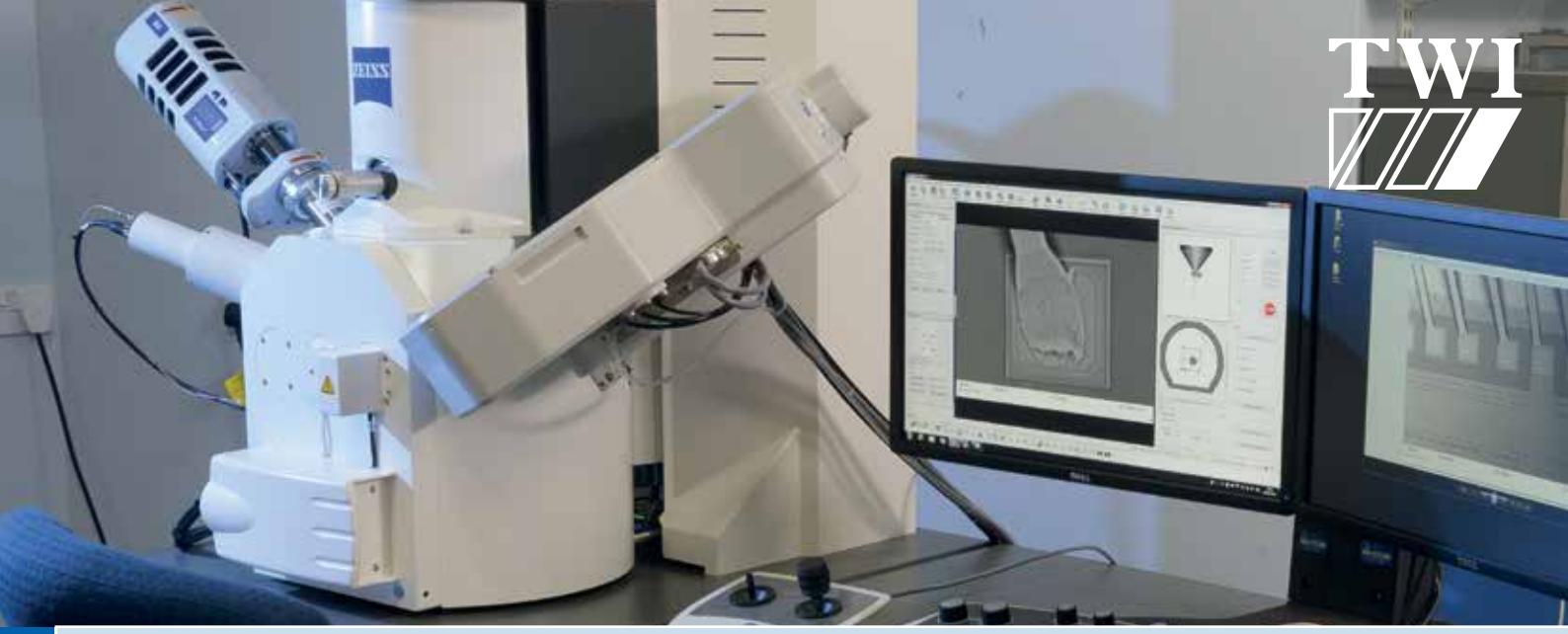


Environmental scanning electron microscope

Zeiss EVO LS15 SEM

High-performance LaB_6 environmental scanning electron microscope with EDX and WDX microanalysis capability.

Features and benefits

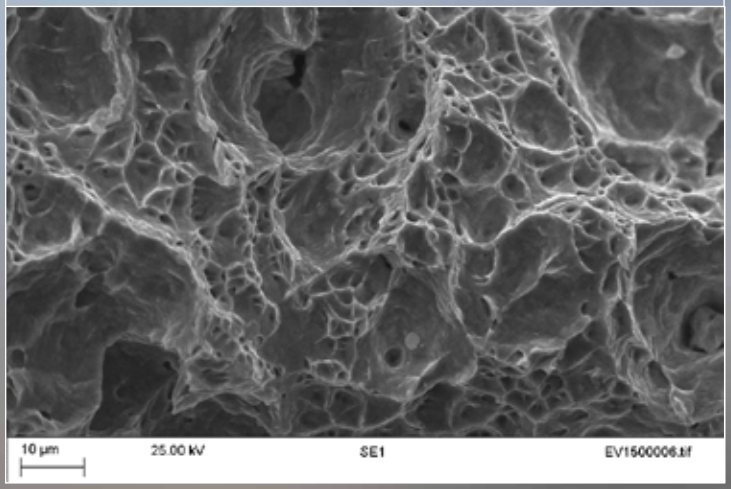
- EasyVP™ providing changeover from HV to VP without the need to exchange pressure limiting apertures
- 'Unrivalled' low kV and VP imaging performance particularly for non-conductive, delicate or biological samples
- High-resolution imaging in various imaging modes in order to capture topographic and compositional information (and combinations thereof)
- Rapid mapping of elemental distribution
- Semi-quantitative and quantitative chemical analysis for identification of elemental composition
- WDX for quantitative micro-analysis of light elements
- Automated chemical analysis, including simultaneous EDX and WDX data acquisition

Some applications

- High resolution imaging of the topography of surfaces of non-metallic materials without the need for coating
- Quantitative analysis of all elements, including light and trace elements, in individual phases within metallic materials

Technical specification

- High vacuum mode and variable pressure environmental mode (10 to 3000 Pa)
- High-resolution imaging in secondary electron, and backscatter electron modes in high vacuum and variable pressure modes, including variable pressure secondary electron detector (VPSE G3)
- High-resolution imaging of all specimens including wet biological and dynamic processes involving liquid water
- Oxford Instruments X-Max^N silicon drift detector for fast energy-dispersive X-ray spectroscopy (EDX) chemical analysis, including chemical distribution mapping
- Oxford Instruments 'Wave' WDX (wavelength dispersive X-ray) quantitative micro-analysis



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